

Recitation 12: CMOS Noise Margin

Yesterday we talked about a CMOS Inverter (Figure 1 part a). Compared with a NMOS inverter (Figure 1 part b), the resistor R is replaced with a PMOS:

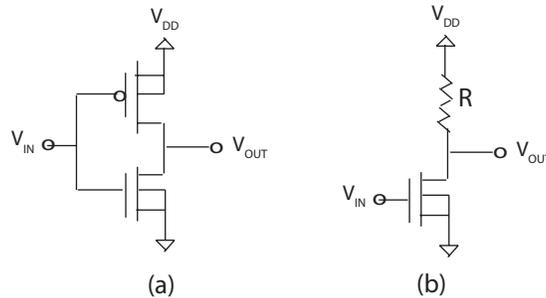


Figure 1: CMOS vs. N-MOS inverter

Today we will focus on the noise margin of a CMOS inverter. To consider the noise margin, we first need the transfer characteristic (i.e. $V_{out} - V_{in}$)

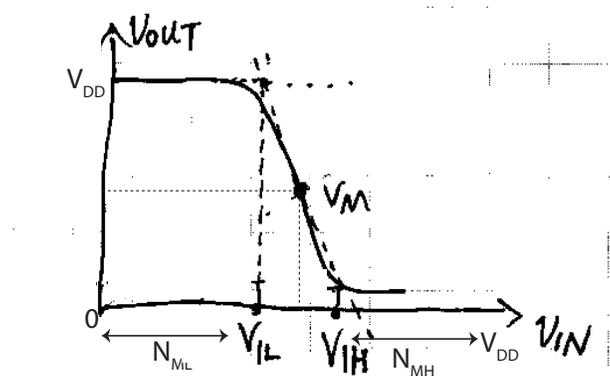


Figure 2:

$$V_{o,\max} = V_{DD} \text{ this is our } V_{OH}$$

$$V_{o,\min} = 0 \text{ this is our } V_{OL}$$

$$\begin{aligned} \therefore N_{MH} &= V_{OH} - V_{IH} \\ &= V_{DD} - V_{IH} \text{ can be seen on Figure 2} \end{aligned}$$

$$N_{ML} = V_{IL} - V_{OL} \text{ can be seen on Figure 2}$$

To find noise margin, or V_{IH} or V_{IL} , we will need voltage V_M and the slope (gain) at V_M .

From simple geometry, one can derive:

$$N_{ML} = V_M - \frac{V_{DD} - V_M}{|A_V|}$$

$$N_{MH} = V_{DD} - V_M - \frac{V_M}{|A_V|}$$

Note: A_V at V_M is negative, and $|A_V|$ is absolute value.

How to find V_M ?

V_M is the point when both NMOS and PMOS are in saturation:

$$I_{D_n} = -I_{D_p}$$

$$\frac{w_n}{2L_n} \mu_n C_{ox} (V_{GS_n} - V_{T_n})^2 = \frac{w_p}{2L_p} \mu_p C_{ox} (V_{SG_p} + V_{T_p})^2$$

We let

$$k_n = \frac{w_n}{L_n} \mu_n C_{ox}$$

$$k_p = \frac{w_p}{L_p} \mu_p C_{ox}$$

Note: Very useful for MOSFET circuit designer: $\frac{w}{L}$ and for the process engineer: μ_n, C_{ox} and μ_p

$$\frac{1}{2} k_n (V_M - V_{T_n})^2 = \frac{1}{2} k_p (V_{DD} - V_M + V_{T_p})^2$$

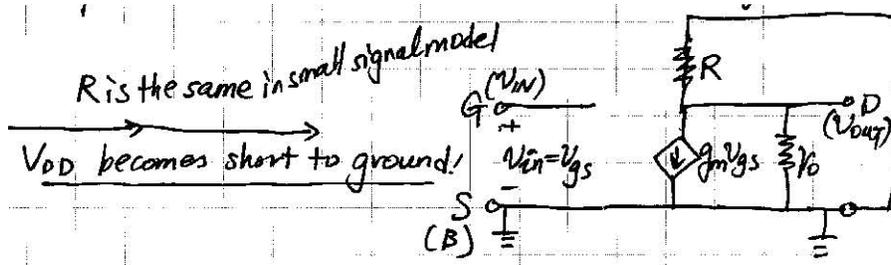
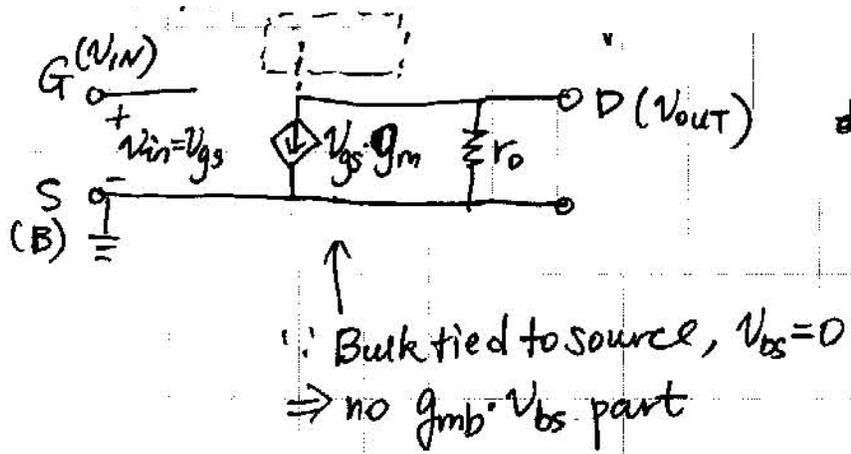
$$V_M = \frac{V_{T_n} + \sqrt{\frac{k_p}{k_n}} (V_{DD} + V_{T_p})}{1 + \sqrt{\frac{k_p}{k_n}}}$$

Usually, V_{T_n}, V_{T_p} are known, if we have V_M , we can find $\frac{k_p}{k_n}$, or vice versa.

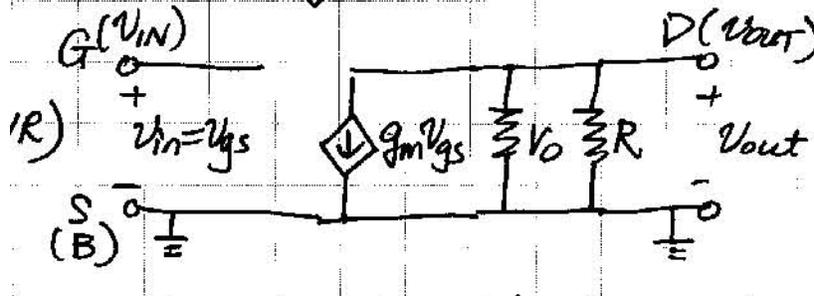
How to find $|A_V(V_M)|$?

Last time, for n-MOS inverter, we did not have much time to look at the gain either. We can look at the gain of the NMOS inverter, which is easier.

Take the circuit of Figure 1 part(b), first replace the N-MOS with its small-signal model:



flip R to make it better



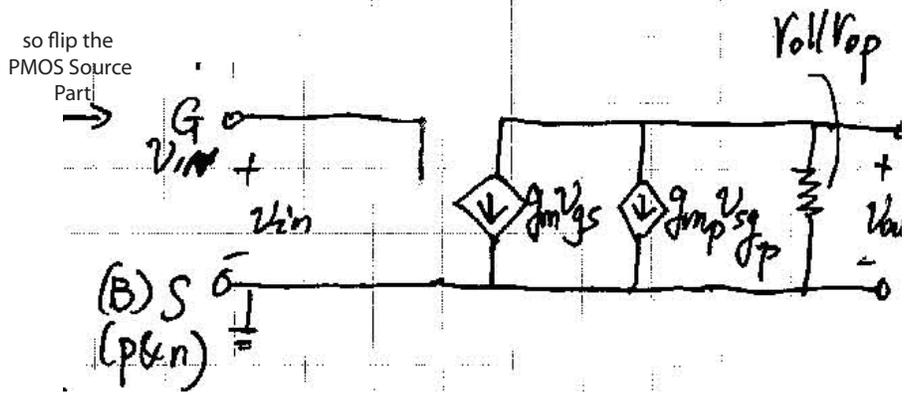
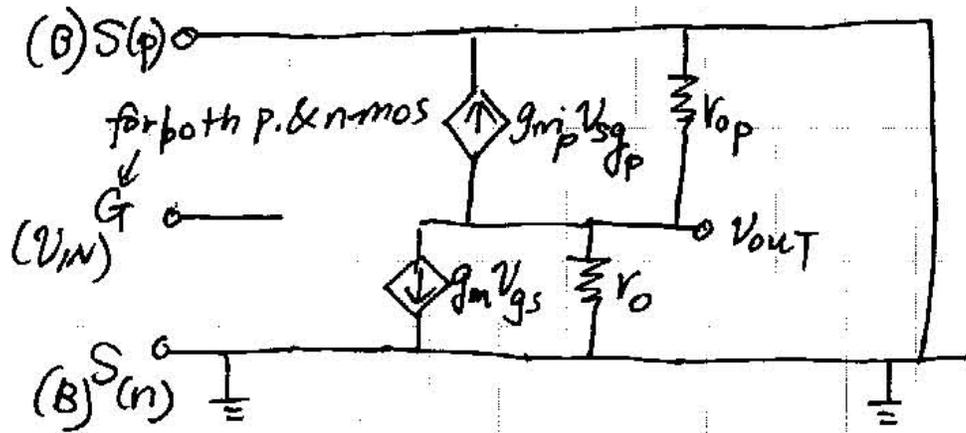
Then:

$$A_v = \frac{V_{out}}{V_{in}} \Big|_{V_M}$$

$$= \frac{\overbrace{g_m V_{gs}}^{\text{current}} \cdot (r_o \parallel R)}{v_{gs}} = -g_m (r_o \parallel R)$$

Small Signal Model of CMOS Inverter

To get the small signal model of CMOS inverter, take the circuit of Figure 1 part (a),



$$\begin{aligned}
V_{in} &= V_{gs} = V_{sgp} \\
A_V \Big|_{V_M} &= \frac{V_{out}}{V_{in}} \Big|_{V_M} = - \frac{(g_{mn} + g_{mp}) V_{in} \cdot (r_{on} || r_{op})}{V_{in}} \\
&= -(g_{mn} + g_{mp}) \cdot (r_{on} || r_{op}) = - \frac{g_{mn} + g_{mp}}{g_{on} + g_{op}} \\
g_{mn} &= \frac{\delta i_{D_n}}{\delta V_{GS}} \Big|_{V_M} = \frac{w_n}{L_n} \mu_n C_{ox} (V_M - V_{T_n}) = \sqrt{\frac{2w_n}{L_n} \mu_n C_{ox} I_{D_n}} = \sqrt{2k_n I_D} \\
g_{mp} &= \frac{\delta i_{D_p}}{\delta V_{SG}} \Big|_{V_M} = \frac{w_p}{L_p} \mu_p C_{ox} (V_{DD} - V_M + V_{T_p}) = \sqrt{\frac{2w_p}{L_p} \mu_p C_{ox} I_{D_p}} = \sqrt{2k_p (-I_{D_p})} \\
g_{on} &= \frac{\delta i_{D_n}}{\delta V_{DS}} \Big|_{V_M} = \lambda_n I_{D_n} \\
g_{op} &= \frac{-\delta i_{D_p}}{\delta V_{SD}} \Big|_{V_M} = \lambda_p (-I_{D_p})
\end{aligned}$$

Exercise

CMOS inverter design specification: $V_M = 2.5 \text{ V}$, $V_{DD} = 5 \text{ V}$.

$$\begin{aligned}
I_{D_n} &= -I_{D_p} = 200 \mu\text{A at } V_{IN} = V_M \\
N_{ML} &= N_{MH} \geq 2.25 \text{ V}
\end{aligned}$$

Find specific maximum λ that can be tolerated to meet design specifications (in terms of NM or noise margin). Assume $\lambda_n = \lambda_p$.

Device data:

$$\begin{aligned}
\mu_n C_{ox} &= 2\mu_p C_{ox} = 50 \mu\text{A/V}^2 \\
V_{T_n} &= -V_{T_p} = 1 \text{ V}
\end{aligned}$$

Because noise margin $\geq 2.25 \text{ V}$,

$$\begin{aligned}
N_{ML} &= V_M - \frac{V_{DD} - V_M}{|A_V|} \geq 2.25 \\
\frac{V_{DD} - V_M}{|A_V|} &\leq V_M - 2.25 = 0.25 \text{ V} \\
|A_V| &\geq \frac{2.5 \text{ V}}{0.25 \text{ V}} = 10 \\
|A_V| &= \frac{g_{mn} + g_{mp}}{g_{op} + g_{on}} \\
g_{mn} &= \sqrt{2k_n I_D} \quad g_{mp} = \sqrt{2k_p I_D} \\
g_{on} &= \lambda_n I_D \\
g_{op} &= \lambda_p I_D \\
I_D &= |-I_{D_p}| = |I_{D_n}|
\end{aligned}$$

We have information of I_D , we need to find k_n, k_p then we find λ_n, λ_p .

$$\because V_{T_n} = -V_{T_p}, V_M = \frac{V_{DD}}{2}, \text{ symmetric : } \sqrt{\frac{k_n}{k_p}} = 1 \text{ or } k_n = k_p$$

$$\frac{1}{2}k_n(V_M - V_{T_n})^2 = I_{D_n} = 200 \mu\text{A}$$

$$k_n = \frac{400 \mu\text{A} \times 2}{(2.5 - 1)^2, \text{V}^2} = 355 \mu\text{A}/\text{V}^2 = k_p$$

$$g_{mn} = g_{mp} = \sqrt{2k_n I_D} = \sqrt{2 \times 355 \mu\text{A}/\text{V}^2 \times 200 \mu\text{A}} = 376.8 \mu\text{A}/\text{V} = 0.376 \text{ ms}$$

$$|A_V| = \frac{g_{mn} + g_{mp}}{\lambda_n I_D + \lambda_p I_D} \geq 10 \implies \lambda_n \text{ or } \lambda_p \leq \frac{2 \times 0.376 \text{ ms}}{10 \times 200 \mu\text{A}} = 0.376 \text{ V}^{-1}$$

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